

**Search Notes**

Application/Control No.

09/664,565

Examiner

Hanh Nguyen

Applicant(s)/Patent and  
Re examination

NAIK, TEJAS

Art Unit

2662

**SEARCHED**

Class	Subclass	Date	Examiner
370	238	6/10/2005	HN
	395.1		
	392		
	400		
	396		
	397		
	216		
	218		
	399	9/11/2005	HN
	338		
	404		
	401		
	409		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	6/10/2005	HN
East	9/11/2005	HN